

MMD80R1K2QZ

800V 1.2Ω N-channel MOSFET

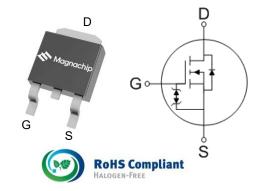
Description

MMD80R1K2QZ is power MOSFET using Magnachip's advanced super junction technology that can realize very low on-resistance and gate charge. It will provide much high efficiency by using optimized charge coupling technology. These user friendly devices give an advantage of Low EMI to designers as well as low switching loss.

Key Parameters

Parameter	Value	Unit
V_{DS} @ $T_{j,max}$	850	V
$R_{DS(on),max}$	1.2	Ω
$V_{GS(th),typ}$	3.5	V
I _D	4.5	Α
$Q_{g,typ}$	11	nC

■ Package & Internal Circuit



■ Features

- Low Power Loss by High Speed Switching and Low On-Resistance
- Excellent ESD robustness
- 100% Avalanche Tested
- Green Package Pb Free Plating, Halogen Free

Applications

- PFC Power Supply Stages
- Switching Applications
- Adapter

Ordering Information

Order Code	Marking	Temp. Range	Package	Packing	RoHS Status
MMD80R1K2QZRH	80R1K2QZ	-55 ~ 150 °C	TO-252(2L)	Reel	Compliant



■ Absolute Maximum Rating (T_c=25 °C unless otherwise specified)

Parameter	Symbol	Rating	Unit	Note
Drain – Source voltage	$V_{ extsf{DSS}}$	800	V	
Gate – Source voltage	V _{GSS}	±30	V	
Continuous dusin summent		4.5	Α	T _C =25 °C
Continuous drain current	l _D	2.85	Α	T _C =100 °C
Pulsed drain current ⁽¹⁾	I _{DM}	13.5	Α	
Power dissipation	P _D	39	W	
Single - pulse avalanche energy	E _{AS}	170	mJ	
MOSFET dv/dt ruggedness	dv/dt	50	V/ns	
Diode dv/dt ruggedness ⁽²⁾	dv/dt	15	V/ns	
Storage temperature	T_{stg}	-55 ~150	°C	
Maximum operating junction temperature	Tj	150	°C	

¹⁾ Pulse width t_P limited by T_{j,max}

■ Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case max	R _{thjc}	3.2	°C /W
Thermal resistance, junction-ambient max	R _{thja}	62.5	°C /W

²⁾ $I_{SD} \leq I_{D}, V_{DS peak} \leq V_{(BR)DSS}$



■ Static Characteristics (T_c=25 °C unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Drain – Source Breakdown voltage	V _{(BR)DSS}	800	-	-	V	$V_{GS} = 0V, I_D = 0.25mA$
Gate Threshold Voltage	$V_{GS(th)}$	2.5	3.5	4.5	٧	$V_{DS} = V_{GS}, I_{D} = 0.25 \text{mA}$
Zero Gate Voltage Drain Current	I _{DSS}	-	-	1	uA	V _{DS} = 800V, V _{GS} = 0V
Gate Leakage Current	I _{GSS}	-	-	10	uA	$V_{GS} = \pm 20V, V_{DS} = 0V$
Drain-Source On State Resistance	R _{DS(ON)}	-	0.95	1.2	Ω	V _{GS} = 10V, I _D = 2.5A

■ Dynamic Characteristics (T_c=25 °C unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Input Capacitance	C _{iss}	-	349	-	_	V _{DS} = 100V, V _{GS} = 0V, f = 400kHz
Output Capacitance	Coss	-	16	-		
Reverse Transfer Capacitance	C _{rss}	-	0.9	-	pF	
Effective Output Capacitance Energy Related ⁽³⁾	C _{o(er)}	-	9.5	-		$V_{DS} = 0V \text{ to } 640V, V_{GS} = 0V, f = 400kHz$
Turn On Delay Time	$t_{d(on)}$	-	16	-	ns	$V_{GS} = 10V, R_G = 25\Omega,$ $V_{DS} = 400V, I_D = 4.5A$
Rise Time	t _r	-	24	-		
Turn Off Delay Time	$t_{d(off)}$	-	59	-		
Fall Time	t _f	-	19	-		
Total Gate Charge	Q_g	-	11	-		
Gate – Source Charge	Q_{gs}	-	3.3	-	nC	$V_{GS} = 10V, V_{DS} = 640V,$ $I_{D} = 4.5A$
Gate – Drain Charge	Q_{gd}	-	4.5	-		
Gate Resistance	R_G	-	21	-	Ω	V _{GS} = 0V, f = 1.0MHz

³⁾ $C_{\text{o(er)}}$ is a capacitance that gives the same stored energy as C_{OSS} while V_{DS} is rising from 0V to 80% $V_{(BR)DSS}$



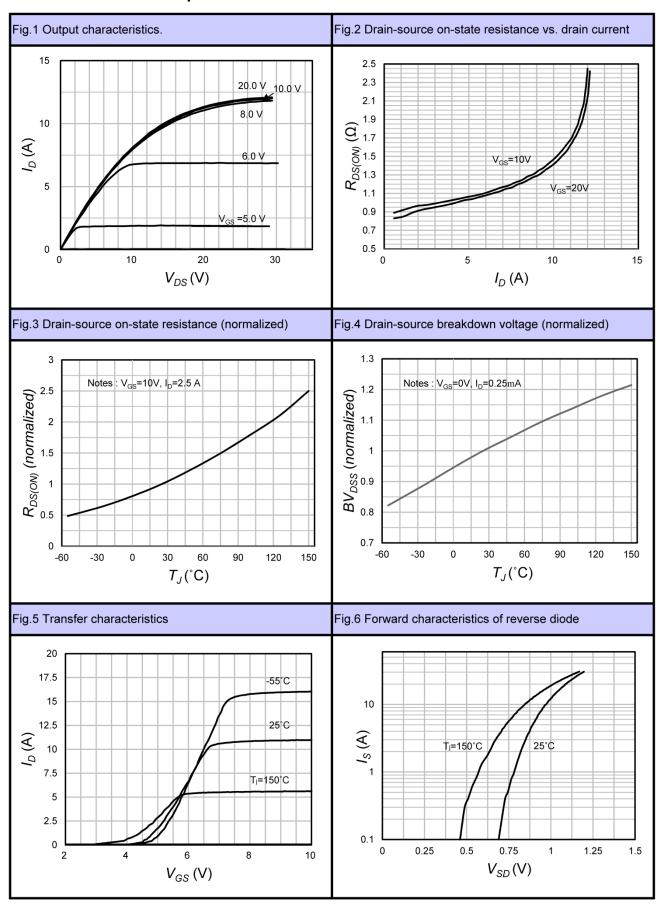
■ Reverse Diode Characteristics (T_c=25 °C unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Continuous Diode Forward Current	Is	-	-	4.5	Α	
Diode Forward Voltage	V_{SD}	-	-	1.4	V	$I_S = 4.5A, V_{GS} = 0V$
Reverse Recovery Time	t _{rr}	-	380	ı	ns	1 450
Reverse Recovery Charge	Qrr	-	2	-	uC	$I_S = 4.5A$ di/dt = 100A/us $V_{DD} = 100V$
Reverse Recovery Current	I _{rrm}	-	11	-	Α	V _{DD} = 100 V

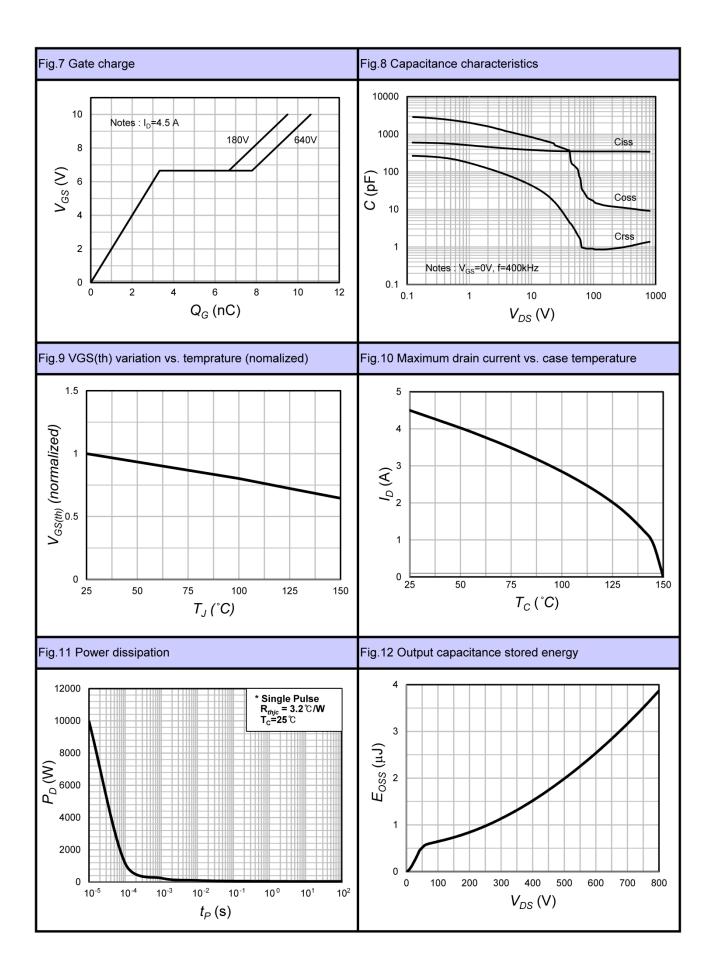
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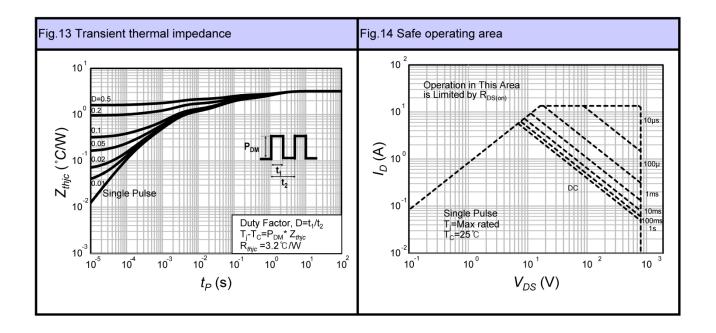
■ Characteristic Graph













■ Test Circuit

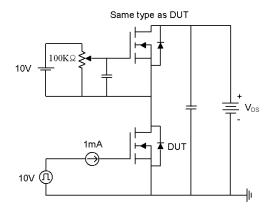


Fig15-1. Gate charge measurement circuit

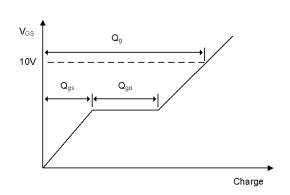


Fig15-2. Gate charge waveform

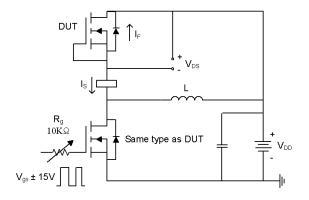


Fig16-1. Diode reverse recovery test circuit

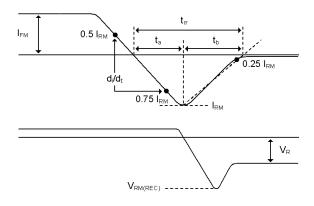


Fig16-2. Diode reverse recovery test waveform

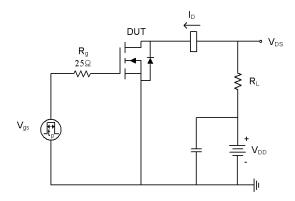


Fig17-1. Switching time test circuit for resistive load

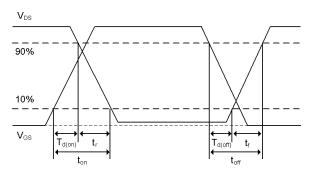


Fig17-2. Switching time waveform

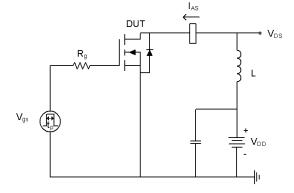


Fig18-1. Unclamped inductive load test circuit

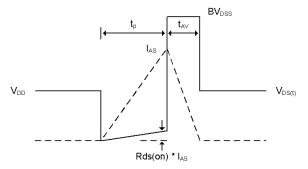
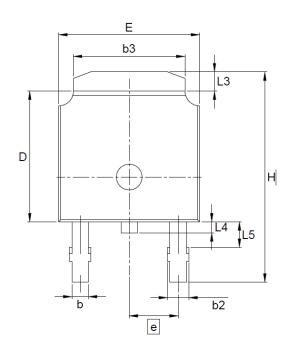


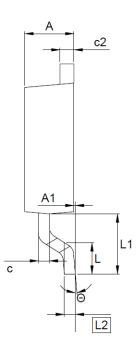
Fig18-2. Unclamped inductive waveform

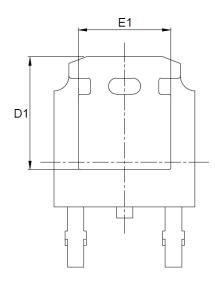


■ Physical Dimension

TO-252(2L)







Symbol	Di	m)		
Symbol	Min	Nom	Max	
E	6.35	-	6.73	
L	1.40	1,52	1,78	
L1		2.74 REF		
L2		0,508 BSC		
L3	0.89	-	1,27	
L4	-	-	1,02	
L5	-	-	1,52	
D	5.97	6.10	6,22	
Н	9.40	-	10.41	
b	0.64	-	0.89	
b2	0.76	-	1.14	
b3	4.95	-	5,46	
е		2,286 BSC		
Α	2,18	-	2,39	
A1	-	-	0,13	
С	0.46	-	0,61	
c2	0.46	_	0.89	
D1	5,21	-	-	
E1	4.32	4.32 -		
Θ	0°	-	10°	

Note: Package body size, length and width do not include mold flash, protrusions and gate burrs.



DISCLAIMER:

The Products are not designed for use in hostile environments, including, without limitation, aircraft, nuclear power generation, medical appliances, and devices or systems in which malfunction of any Product can reasonably be expected to result in a personal injury. Seller's customers using or selling Seller's products for use in such applications do so at their own risk and agree to fully defend and indemnify Seller.

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